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|-----------------------------------|---------------------------------------|--|---|-------------|
| Notice of References Cited | Application/Control No. 10/774,723 | | Applicant(s)/Patent Under Reexamination TORRES ET AL. | |
| | Examiner TRANG DOAN | | Art Unit 2131 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------------|----------------|
| * | A | US-6,182,229 | 01-2001 | Nielsen, Jakob | 726/8 |
| * | B | US-7,200,804 | 04-2007 | Khavari et al. | 715/230 |
| * | C | US-2005/0033968 | 02-2005 | Dupouy et al. | 713/183 |
| * | D | US-7,191,466 | 03-2007 | Hamid et al. | 726/3 |
| * | E | US-7,185,272 | 02-2007 | Pearce et al. | 715/207 |
| * | F | US-7,136,490 | 11-2006 | Martinez et al. | 380/284 |
| * | G | US-6,484,263 | 11-2002 | Liu, Te-Kai | 726/8 |
| * | H | US-2002/0023108 | 02-2002 | DASWANI et al. | 707/507 |
| * | I | US-2002/0186249 | 12-2002 | Lu et al. | 345/781 |
| * | J | US-6,865,680 | 03-2005 | Wu et al. | 726/12 |
| * | K | US-6,954,862 | 10-2005 | Serpa, Michael Lawrence | 726/5 |
| * | L | US-7,310,733 | 12-2007 | Pearson et al. | 713/185 |
| * | M | US-6,859,878 | 02-2005 | Kerr et al. | 713/183 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | | |
|---|---|---|--|--|--|--|
| | U | Netissimo, The Portable Netissimo Solution, December 2, 2002, pages 1-8. | | | | |
| | V | | | | | |
| | W | | | | | |
| | X | | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.